

## Ten publications most relevant for the application

1. Karvonen E, Lassas M, Pankka P and Siltanen S **2024**, *TILT: Topological interface recovery in limited-angle tomography*. SIAM Journal of Imaging Sciences 17(3): pp. 1761–1794.
2. Juvonen M, Siltanen S and Moura F **2023**, *Helsinki deblur challenge 2021: Description of photographic data* Inverse Problems and Imaging 17(5): pp. 1008–1023.
3. Rautio S, Murthy R, Bubba TA, Lassas M and Siltanen S **2023**, *Learning a microlocal prior for limited-angle tomography*. IMA Journal of Applied Mathematics 88(6): pp. 888–916.
4. Kekkonen H, Lassas M, Saksman E and Siltanen S **2023**, *Random tree Besov priors—Towards fractal imaging*. Inverse Problems and Imaging 17(2): pp. 507–531.
5. Bubba TA, Galinier M, Lassas M, Prato M, Ratti L and Siltanen S **2021**, *Deep neural networks for inverse problems with pseudodifferential operators: An application to limited-angle tomography*. SIAM Journal on Imaging Sciences 14(2), pp. 470–505.
6. Backholm R, Bubba T A, Bélanger-Champagne C, Helin T, Dendooven P and Siltanen S **2020**, *Simultaneous Reconstruction of Emission and Attenuation in Passive Gamma Emission Tomography of Spent Nuclear Fuel*. Inverse Problems and Imaging, 14(2), pp. 317–337.
7. Bubba T A, Heikkilä T, Help H, Huotari S, Salmon Y and Siltanen S **2020**, *Sparse dynamic tomography. A shearlet-based approach for iodine perfusion in plant stems*. Inverse Problems 36, 094002.
8. Lytle G, Perry P and Siltanen S **2020**, *Nachman's reconstruction for the Calderón problem with discontinuous conductivities*. Inverse Problems 36 035018
9. Siltanen S and Ide T **2020**, Electrical impedance tomography, enclosure method and machine learning. 2020 IEEE 30th International Workshop on Machine Learning for Signal Processing (MLSP). IEEE, 2020. pp. 1-6.
10. Mueller J L and Siltanen S **2012**, *Linear and Nonlinear Inverse Problems with Practical Applications*, SIAM Computational Science and Engineering 10.